

<b>Notice of References Cited</b>	Application/Control No. 10/786,495		Applicant(s)/Patent Under Reexamination LIN ET AL.	
	Examiner Sang Nguyen		Art Unit 2886	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,674,510	01-2004	Jasper et al.	355/55
*	B	US-6,975,407	12-2005	Wang et al.	356/601
*	C	US-5,283,141	02-1994	Yoon et al.	430/30
*	D	US-4,890,239	12-1989	Ausschnitt et al.	430/30
*	E	US-5,283,141	02-1994	Yoon et al.	430/30
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.